


Search Notes 	Application/Control No. 10526520	Applicant(s)/Patent Under Reexamination SCHULIST ET AL.
	Examiner Nguyen, Hai V	Art Unit 2618

SEARCHED

Class	Subclass	Date	Examiner
370	335	12/22/2007	HN
455	517	12/30/2009	HN

SEARCH NOTES

Search Notes	Date	Examiner
EAST search (US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB) (see search history printout report)	12/21/2007; 01/03/2008	HN
EAST search updated	05/29/2008	HN
EAST search updated (see search history printout report)	01/10/2009	HN
EAST search updated (see search history printout report)	10/14/2009	HN
EAST search updated (see search history printout report)	12/30/2009	HN
Interference search (see search history printout report)	12/30/2009	HN

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner
455	11.1, 90.1-90.3, 403	12/30/2009	HN

--	--